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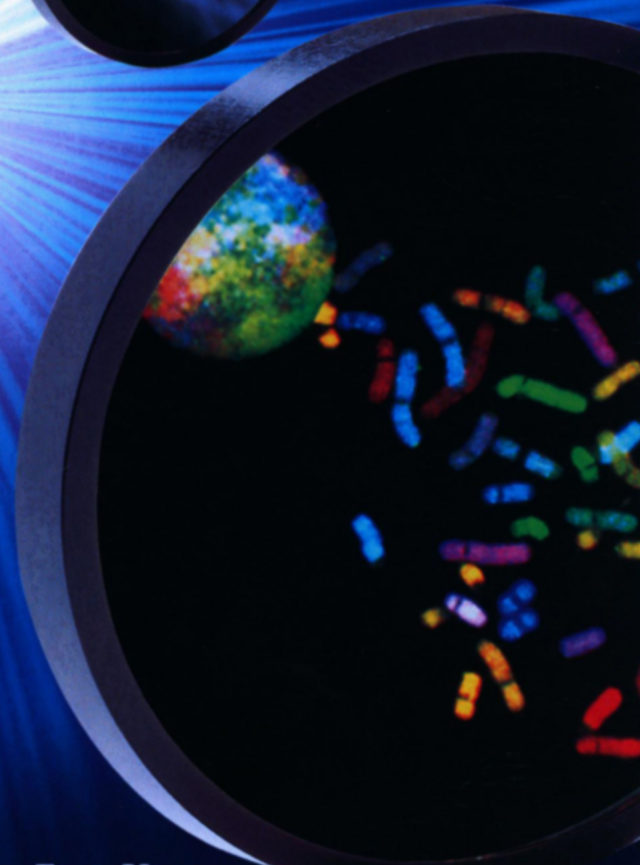
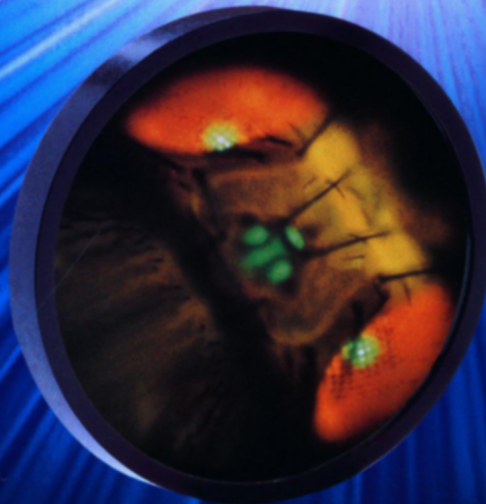
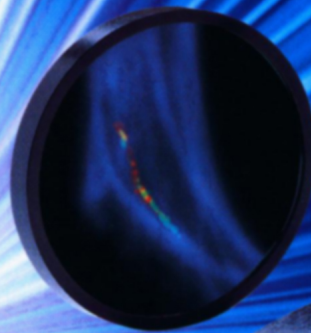
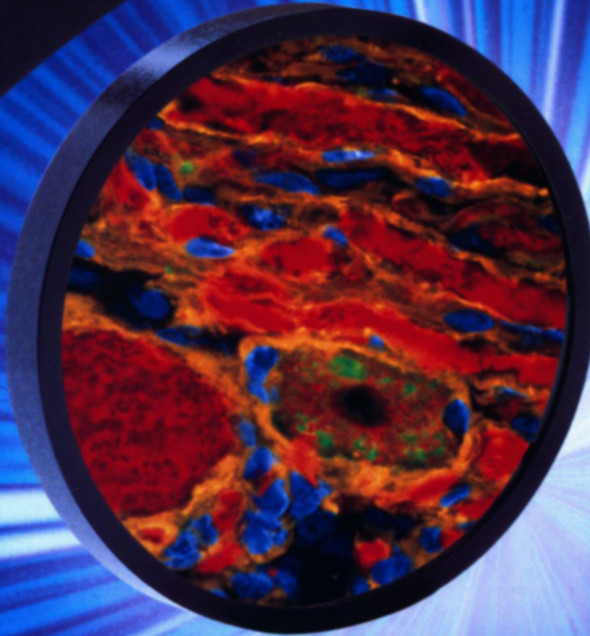


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Editor in Chief

Editor, Microanalysis

Charles E. Lyman
Materials Science and Engineering
Lehigh University
5 East Packer Avenue
Bethlehem, Pennsylvania 18015-3195
Phone: (610) 758-4249
FAX: (610) 758-4244
e-mail: cel1@lehigh.edu

Editor, Biological Applications

Ralph Albrecht
Animal Health and Biomedical Sciences
University of Wisconsin-Madison
1655 Linden Drive
Madison, Wisconsin 53706-1581
Phone: (608) 262-3177
FAX: (608) 262-7420
e-mail: albrecht@ahabs.wisc.edu

Editor, Materials Applications

C. Barry Carter
Chemical Engineering and Materials
Science
151 Amundson Hall
University of Minnesota
Minneapolis, Minnesota 55455-0132
Phone: (612) 625-8805
Fax: (612) 626-7246
e-mail: carter@cems.umn.edu

Editor, Materials Applications

Vinayak P. Dravid
Materials Science and Engineering
Northwestern University
2225 N. Campus Drive, Room 3013A
Evanston, Illinois 60208-3105
Phone: (847) 467-1363
Fax: (847) 491-7820
e-mail: v-dravid@nwu.edu

Editor, Light and Scanning Probe Microscopies

Brian Herman
Cellular and Structural Biology
University of Texas at San Antonio
7703 Floyd Curl Drive
San Antonio, Texas 78284-7762
Phone: (210) 567-3800
Fax: (210) 567-3803
e-mail: hermanb@uthscsa.edu

Editor, Biological Applications

Heide Schatten
Veterinary Pathobiology
University of Missouri-Columbia
1600 E. Rollins Street
Columbia, Missouri 65211
Phone: (573) 882-2396
Fax: (573) 884-5414
e-mail: schattenh@missouri.edu

News and Commentary Editor

Book Review Editor

JoAn Hudson
Phone: (864) 656-2465
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Special Section Editor

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Phone: (518) 474-2811
Fax: (518) 474-8590
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Expo Editor

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Phone: (419) 383-5256
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Proceedings Editor

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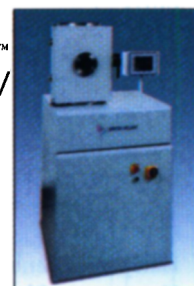
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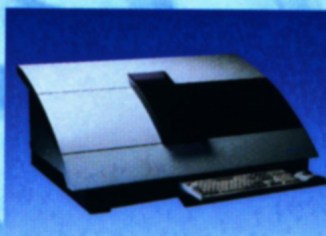
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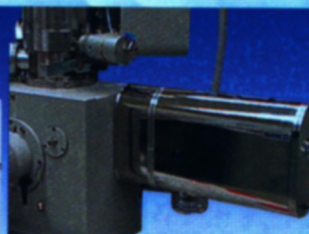
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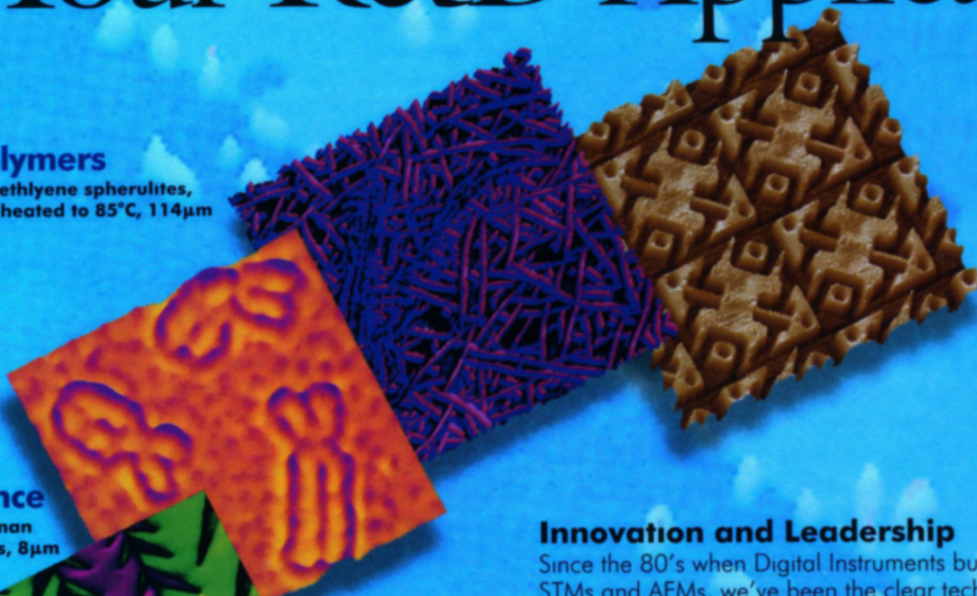
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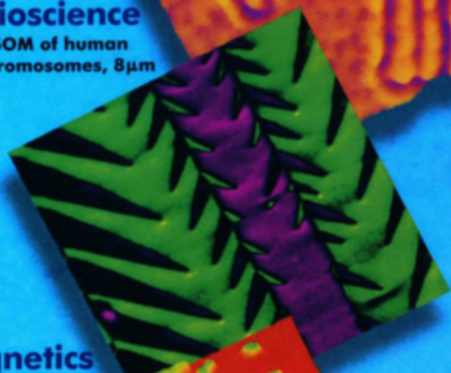


MEMS

DMD™ array, courtesy
Texas Instruments 25µm

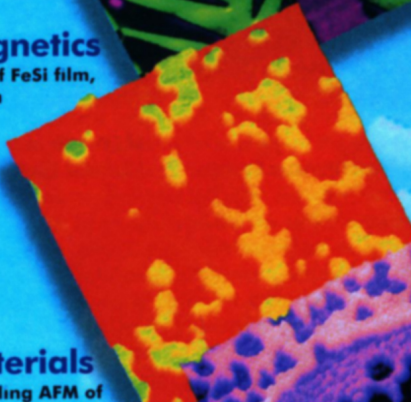
Bioscience

NSOM of human
chromosomes, 8µm



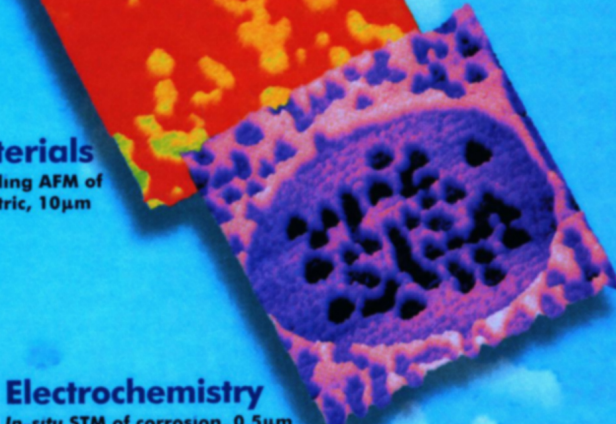
Magnetics

MFM of FeSi film,
110µm



Materials

Tunneling AFM of
dielectric, 10µm



Electrochemistry

In situ STM of corrosion, 0.5µm

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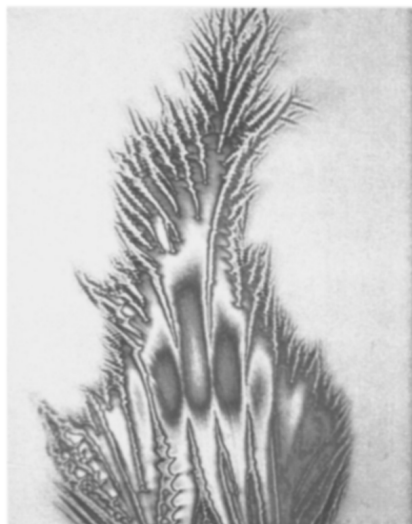
(Background) Ultrathin layer of
polystyrene b PMMA, 10µm

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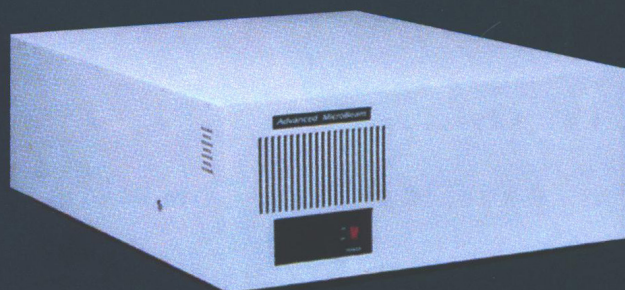
On the Cover: Visible-light image from a (110) surface of rutile annealed at 1400°C in air. The presence of fine particles on the surface gives rise to the interference pattern. (The image was kindly provided by N. (Ravi) Ravishanker and C. Barry Carter, Department of Chemical Engineering and Materials Science, University of Minnesota, Minneapolis, MN.)

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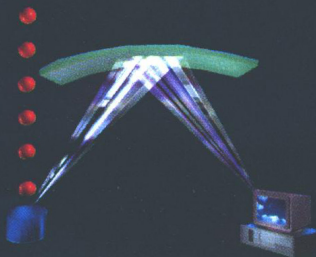
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